

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

100331

Low Power Triple D Flip-Flop

General Description

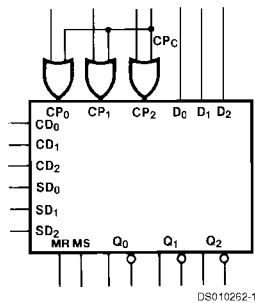
The 100331 contains three D-type, edge-triggered master/slave flip-flops with true and complement outputs, a Common Clock (CP_C), and Master Set (MS) and Master Reset (MR) inputs. Each flip-flop has individual Clock (CP_n), Direct Set (SD_n) and Direct Clear (CD_n) inputs. Data enters a master when both CP_n and CP_C are LOW and transfers to a slave when CP_n or CP_C (or both) go HIGH. The Master Set, Master Reset and individual CD_n and SD_n inputs override the Clock inputs. All inputs have 50 k Ω pull-down resistors.

Features

- 35% power reduction of the 100131
- 2000V ESD protection
- Pin/function compatible with 100131
- Voltage compensated operating range = -4.2V to -5.7V
- Available to industrial grade temperature range
- Available to MIL-STD-883

Ordering Code:

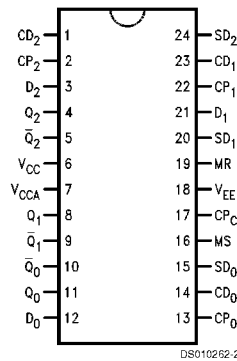
Logic Symbol



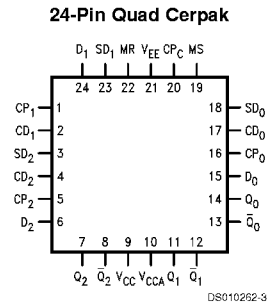
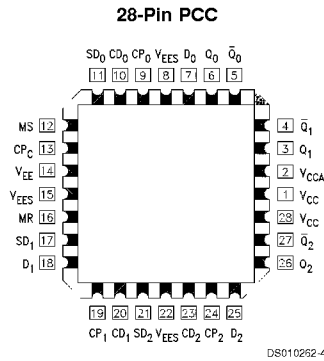
Pin Names	Description
CP_0 - CP_2	Individual Clock Inputs
CP_C	Common Clock Input
D_0 - D_2	Data Inputs
CD_0 - CD_2	Individual Direct Clear Inputs
SD_n	Individual Direct Set Inputs
MR	Master Reset Input
MS	Master Set Input
Q_0 - Q_2	Data Outputs
\bar{Q}_0 - \bar{Q}_2	Complementary Data Outputs

Connection Diagrams

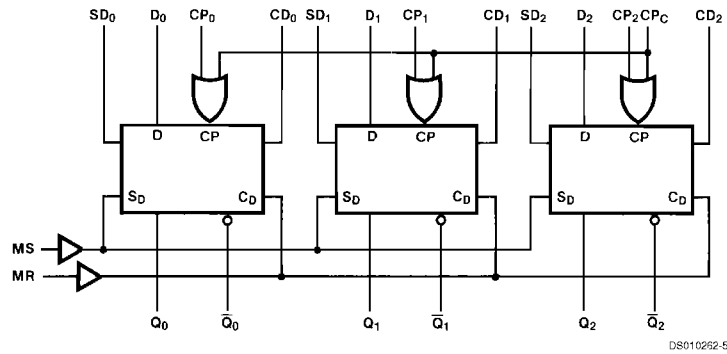
24-Pin DIP/SOIC



Connection Diagrams (Continued)



Logic Diagram



Truth Tables

Synchronous Operation

(Each Flip-Flop)

D _n	Inputs				Outputs Q _n (t + 1)
	CP _n	CP _C	MS SD _n	MR CD _n	
L	↗	L	L	L	L
H	↗	L	L	L	H
L	L	↗	L	L	L
H	L	↗	L	L	H
X	L	L	L	L	Q _n (t)
X	H	X	L	L	Q _n (t)
X	X	H	L	L	Q _n (t)

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Don't Care
 U = Undefined
 t = Time before CP Positive Transition
 t + 1 = Time after CP Positive Transition
 ↗ = LOW to HIGH Transition

Asynchronous Operation

(Each Flip-Flop)

Inputs					Outputs
D _n	CP _n	CP _C	MS SD _n	MR CD _n	Q _n (t + 1)
X	X	X	H	L	H
X	X	X	L	H	L
X	X	X	H	H	U

Absolute Maximum Ratings (Note 1)

Above which the useful life may be impaired

Storage Temperature (T_{STG})	-65°C to +150°C
Maximum Junction Temperature (T_J)	
Ceramic	+175°C
Plastic	+150°C
Pin Potential to Ground Pin (V_{EE})	-7.0V to +0.5V
Input Voltage (DC)	V_{EE} to +0.5V
Output Current (DC Output HIGH)	-50 mA
ESD (Note 2)	≤ 2000V

Recommended Operating Conditions

Case Temperature (T_C)	
Commercial	0°C to +85°C
Industrial	-40°C to +85°C
Military	-55°C to +125°C
Supply Voltage (V_{EE})	-5.7V to -4.2V

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Commercial Version

DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = 0°C$ to $+85°C$ (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions	
V_{OH}	Output HIGH Voltage	-1025	-955	-870	mV	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to -2.0V
V_{OL}	Output LOW Voltage	-1830	-1705	-1620	mV		
V_{OHC}	Output HIGH Voltage	-1035			mV	$V_{IN} = V_{IH}$ (Min) or V_{IL} (Max)	Loading with 50Ω to -2.0V
V_{OLC}	Output LOW Voltage			-1610	mV		
V_{IH}	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs	
V_{IL}	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs	
I_{IL}	Input LOW Current	0.5			μA	$V_{IN} = V_{IL}$ (Min)	
I_{IH}	Input HIGH Current			240	μA	$V_{IN} = V_{IH}$ (Max)	
I_{EE}	Power Supply Current	-122		-65	mA	Inputs Open	

Note 3: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

DIP AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0°C$		$T_C = +25°C$		$T_C = +85°C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
f_{max}	Toggle Frequency	375		375		375		MHz	Figures 2, 3
t_{PLH}	Propagation Delay CP _C to Output	0.75	2.00	0.75	2.00	0.75	2.00	ns	Figures 1, 3
t_{PHL}	CP _n to Output								
t_{PLH}	Propagation Delay CP _n to Output	0.75	2.00	0.75	2.00	0.75	2.00	ns	Figures 1, 4
t_{PHL}	Propagation Delay CD _n , SD _n to Output	0.70	1.70	0.70	1.70	0.70	1.80	ns	
t_{PLH}		0.70	2.00	0.70	2.00	0.70	2.00	ns	
t_{PHL}									
t_{PLH}	Propagation Delay MS, MR to Output	1.10	2.60	1.10	2.60	1.10	2.60	ns	
t_{PHL}		1.10	2.80	1.10	2.80	1.10	2.80	ns	
t_{TLH}	Transition Time	0.35	1.30	0.35	1.30	0.35	1.30	ns	Figures 1, 3, 4
t_{THL}	20% to 80%, 80% to 20%								

DIP AC Electrical Characteristics (Continued)

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t_S	Setup Time								Figure 5
	D_n	0.40		0.40		0.40			ns Figure 4
	CD_n , SD_n (Release Time)	1.30		1.30		1.30			
	MS, MR (Release Time)	2.30		2.30		2.30			
t_H	Hold Time D_n	0.5		0.5		0.7		ns	Figure 5
$t_{pw(H)}$	Pulse Width HIGH CP_n , CP_C , CD_n , SD_n , MR, MS	2.00		2.00		2.00		ns	Figures 3, 4

SOIC, PCC and Cerpak AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions	
		Min	Max	Min	Max	Min	Max			
f_{max}	Toggle Frequency	400		400		400		MHz	Figures 2, 3	
t_{PLH} t_{PHL}	Propagation Delay CP_C to Output	0.75	1.80	0.75	1.80	0.75	1.80	ns	Figures 1, 3	
t_{PLH} t_{PHL}	Propagation Delay CP_n to Output	0.75	1.80	0.75	1.80	0.75	1.80	ns		
t_{PLH} t_{PHL}	Propagation Delay CD_n , SD_n to Output	0.70	1.50	0.70	1.50	0.70	1.60	ns	CP_n , $CP_C = L$	Figures 1, 4
t_{PLH} t_{PHL}		0.80	1.80	0.70	1.80	0.70	1.80		CP_n , $CP_C = H$	
t_{PLH} t_{PHL}	Propagation Delay MS, MR to Output	1.10	2.40	1.10	2.40	1.10	2.40	ns	CP_n , $CP_C = L$	
t_{PLH} t_{PHL}		1.10	2.60	1.10	2.60	1.10	2.60		CP_n , $CP_C = H$	
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	Figures 1, 3, 4	
t_S	Setup Time								Figure 5	
	D_n	0.30		0.30		0.30			ns Figure 4	
	CD_n , SD_n (Release Time)	1.20		1.20		1.20				
	MS, MR (Release Time)	2.20		2.20		2.20				
t_H	Hold Time D_n	0.5		0.5		0.7		ns	Figure 5	
$t_{pw(H)}$	Pulse Width HIGH CP_n , CP_C , CD_n , SD_n , MR, MS	2.00		2.00		2.00		ns	Figures 3, 4	
t_{PLH} t_{PHL}	Propagation Delay CP_C to Output	0.75	1.40	0.75	1.40	0.80	1.50	ns	Figures 1, 3 PCC Only	
t_{PLH} t_{PHL}	Propagation Delay CP_n to Output	0.70	1.40	0.75	1.40	0.80	1.50			

SOIC, PCC and Cerpak AC Electrical Characteristics (Continued)

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions	
		Min	Max	Min	Max	Min	Max			
t_{PLH} t_{PHL}	Propagation Delay CD _n , SD _n to Output	0.70	1.50	0.70	1.50	0.80	1.60	ns	CP _n , CP _C = L PCC Only	Figures 1, 4
t_{PLH} t_{PHL}		0.80	1.70	0.80	1.70	0.80	1.80		CP _n , CP _C = H PCC Only	
t_{PLH} t_{PHL}	Propagation Delay MS, MR to Output	1.10	2.00	1.10	2.00	1.20	2.10	ns	CP _n , CP _C = L PCC Only	
t_{PLH} t_{PHL}		1.20	2.10	1.20	2.10	1.30	2.20		CP _n , CP _C = H PCC Only	
t_{OSHL}	Maximum Skew Common Edge Output-to-Output Variation Common Clock to Output Path		100		100		100	ps	PCC Only (Note 4)	
t_{OSHL}	Maximum Skew Common Edge Output-to-Output Variation CP _n to Output Path		235		235		235	ps	PCC Only (Note 4)	
t_{OSLH}	Maximum Skew Common Edge Output-to-Output Variation Common Clock to Output Path		120		120		120	ps	PCC Only (Note 4)	
t_{OSLH}	Maximum Skew Common Edge Output-to-Output Variation CP _n to Output Path		275		275		275	ps	PCC Only (Note 4)	
t_{OST}	Maximum Skew Opposite Edge Output-to-Output Variation Common Clock to Output Path		125		125		125	ps	PCC Only (Note 4)	
t_{OST}	Maximum Skew Opposite Edge Output-to-Output Variation CP _n to Output Path		265		265		265	ps	PCC Only (Note 4)	
t_{ps}	Maximum Skew Pin (Signal) Transition Variation Common Clock to Output Path		90		90		90	ps	PCC Only (Note 4)	
t_{ps}	Maximum Skew Pin (Signal) Transition Variation CP _n to Output Path		90		90		90	ps	PCC Only (Note 4)	

Note 4: Output-to-Output Skew is defined as the absolute value of the difference between the actual propagation delay for any outputs within the same packaged device. The specifications apply to any outputs switching in the same direction either HIGH to LOW (t_{OSHL}), or LOW to HIGH (t_{OSLH}), or in opposite directions both HL and LH (t_{OST}). Parameters t_{OST} and t_{ps} guaranteed by design.

Industrial Version

PCC DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -40^{\circ}C$ to $+85^{\circ}C$ (Note 5)

Symbol	Parameter	$T_C = -40^{\circ}C$		$T_C = 0^{\circ}C$ to $+85^{\circ}C$		Units	Conditions	
		Min	Max	Min	Max			
V_{OH}	Output HIGH Voltage	-1085	-870	-1025	-870	mV	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to -2.0V
V_{OL}	Output LOW Voltage	-1830	-1575	-1830	-1620	mV		
V_{OHC}	Output HIGH Voltage	-1095		-1035		mV	$V_{IN} = V_{IH}$ (Min) or V_{IL} (Max)	Loading with 50Ω to -2.0V
V_{OLC}	Output LOW Voltage		-1565		-1610	mV		
V_{IH}	Input HIGH Voltage	-1170	-870	-1165	-870	mV	Guaranteed HIGH Signal for All Inputs	
V_{IL}	Input LOW Voltage	-1830	-1480	-1830	1475	mV	Guaranteed LOW Signal for All Inputs	
I_{IL}	Input LOW Current	0.5		0.5		μA	$V_{IN} = V_{IL}$ (Min)	
I_{IH}	Input HIGH Current		300		240	μA	$V_{IN} = V_{IH}$ (Max)	
I_{EE}	Power Supply Current	-122	-60	-122	-65	mA	Inputs Open	

Note 5: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

PCC AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -40^{\circ}C$		$T_C = +25^{\circ}C$		$T_C = +85^{\circ}C$		Units	Conditions	
		Min	Max	Min	Max	Min	Max			
f_{max}	Toggle Frequency	375		400		400		MHz	Figures 2, 3	
t_{PLH}	Propagation Delay	0.75	1.80	0.75	1.80	0.75	1.80	ns	Figures 1, 3	
t_{PHL}	CP_C to Output									
t_{PLH}	Propagation Delay	0.70	1.80	0.75	1.80	0.75	1.80	ns	Figures 1, 4	
t_{PHL}	CP_n to Output									
t_{PLH}	Propagation Delay	0.60	1.50	0.70	1.50	0.70	1.60	ns	$CP_n, CP_C = L$	
t_{PHL}	CD_n, SD_n to Output								$CP_n, CP_C = H$	
t_{PLH}	Propagation Delay MS, MR to Output	1.10	2.40	1.10	2.40	1.10	2.40	ns	$CP_n, CP_C = L$	
t_{PHL}		1.10	2.60	1.10	2.60	1.10	2.60		$CP_n, CP_C = H$	
t_{TLH}	Transition Time	0.20	1.40	0.35	1.10	0.35	1.10	ns	Figures 1, 3, 4	
t_{THL}	20% to 80%, 80% to 20%									
t_S	Setup Time								Figure 5	
	D_n	1.00		0.30		0.30		ns	Figure 4	
	CD_n, SD_n (Release Time)	1.50		1.20		1.20				
	MS, MR (Release Time)	2.50		2.20		2.20				
t_H	Hold Time D_n	0.7		0.5		0.7		ns	Figure 5	
$t_{pw(H)}$	Pulse Width HIGH							ns	Figures 3, 4	
	$CP_n, CP_C, CD_n,$ SD_n, MR, MS	2.00		2.00		2.00				

Military Version

DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^{\circ}C$ to $+125^{\circ}C$

Symbol	Parameter	Min	Max	Units	T_C	Conditions	Notes	
V_{OH}	Output HIGH Voltage	-1025	-870	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	(Notes 6, 7, 8)
		-1085	-870	mV	$-55^{\circ}C$			
V_{OL}	Output LOW Voltage	-1830	-1620	mV	$0^{\circ}C$ to $+125^{\circ}C$			
		-1830	-1555	mV	$-55^{\circ}C$			
V_{OHc}	Output HIGH Voltage	-1035		mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Min) or V_{IL} (Max)	Loading with 50Ω to $-2.0V$	(Notes 6, 7, 8)
		-1085		mV	$-55^{\circ}C$			
V_{OLc}	Output LOW Voltage		-1610	mV	$0^{\circ}C$ to $+125^{\circ}C$			
			-1555	mV	$-55^{\circ}C$			
V_{IH}	Input HIGH Voltage	-1165	-870	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed HIGH Signal for all Inputs	(Notes 6, 7, 8, 9)	
V_{IL}	Input LOW Voltage	-1830	-1475	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed LOW Signal for all Inputs	(Notes 6, 7, 8, 9)	
I_{IL}	Input LOW Current	0.50		μA	$-55^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -4.2V$ $V_{IN} = V_{IL}$ (Min)	(Notes 6, 7, 8)	
I_{IH}	Input HIGH Current		240	μA	$0^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH}$ (Max)	(Notes 6, 7, 8)	
			340	μA	$-55^{\circ}C$			
I_{EE}	Power Supply Current	-130	-50	mA	$-55^{\circ}C$ to $+125^{\circ}C$	Inputs Open	(Notes 6, 7, 8)	

Note 6: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 7: Screen tested 100% on each device at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups, 1, 2, 3, 7 and 8.

Note 8: Sampled tested (Method 5005, Table I) on each manufactured lot at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups A1, 2, 3, 7 and 8.

Note 9: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		Units	Conditions	Notes	
		Min	Max	Min	Max	Min	Max				
f_{max}	Toggle Frequency	400		400		400		MHz	Figures 2, 3	(Note 13)	
t_{PLH} t_{PHL}	Propagation Delay CP _C to Output	0.50	2.20	0.60	2.00	0.50	2.40	ns	Figures 1, 3	(Notes 10, 11, 12)	
t_{PLH} t_{PHL}	Propagation Delay CP _n to Output	0.50	2.20	0.60	2.00	0.50	2.40	ns			
t_{PLH} t_{PHL}	Propagation Delay CD _n , SD _n to Output	0.50	2.20	0.60	2.00	0.50	2.40	ns	CP _n , CP _C = L Figures 1, 4		
t_{PLH} t_{PHL}		0.50	2.40	0.60	2.10	0.50	2.50				CP _n , CP _C = H
t_{PLH} t_{PHL}	Propagation Delay MS, MR to Output	0.70	2.70	0.80	2.60	0.80	2.90	ns	CP _n , CP _C = L		
t_{PLH} t_{PHL}		0.70	2.90	0.80	2.80	0.80	3.10		CP _n , CP _C = H		
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.20	1.40	0.20	1.40	0.20	1.40	ns	Figures 1, 3, 4		
t_s	Setup Time								Figure 5		(Note 13)
	D _n	1.00		0.80		0.90		ns	Figure 4		
	CD _n , SD _n (Release Time) MS, MR (Release Time)	1.50		1.30		1.60					
t_h	Hold Time D _n	1.50		1.30		1.60		ns	Figure 5		
$t_{pw(H)}$	Pulse Width HIGH CP _n , CP _C , CD _n , SD _n , MR, MS	2.00		2.00		2.00		ns	Figures 3, 4		

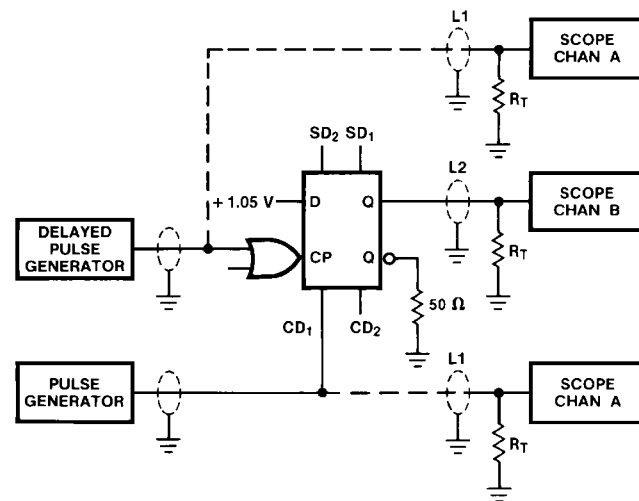
Note 10: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^\circ C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 11: Screen tested 100% on each device at $+25^\circ C$. Temperature only, Subgroup A9.

Note 12: Sample tested (Method 5005, Table I) on each Mfg. lot at $+25^\circ C$, Subgroup A9, and at $+125^\circ C$, and $-55^\circ C$ Temp., Subgroups A10 and A11.

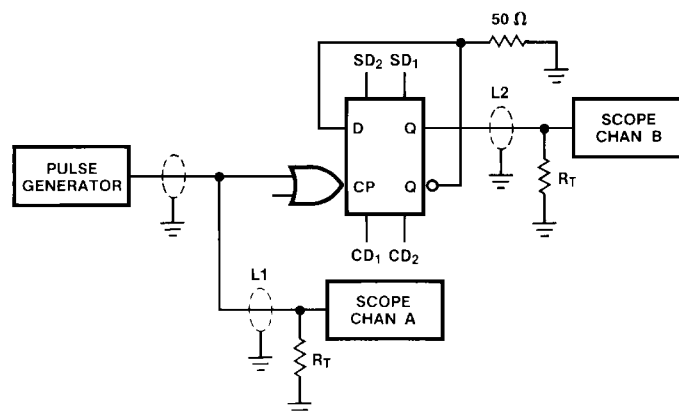
Note 13: Not tested at $+25^\circ C$, $+125^\circ C$ and $-55^\circ C$ Temperature (design characterization data).

Test Circuits



DS010262-6

FIGURE 1. AC Test Circuit



DS010262-7

Notes:

V_{CC} , $V_{CCA} = +2V$, $V_{EE} = -2.5V$

L1 and L2 = Equal length 50Ω impedance lines

$R_T = 50\Omega$ terminator internal to scope

Decoupling 0.1 μF from GND to V_{CC} and V_{EE}

All unused outputs are loaded with 50Ω to GND

C_L = Fixture and stray capacitance ≤ 3 pF

FIGURE 2. Toggle Frequency Test Circuit

Switching Waveforms

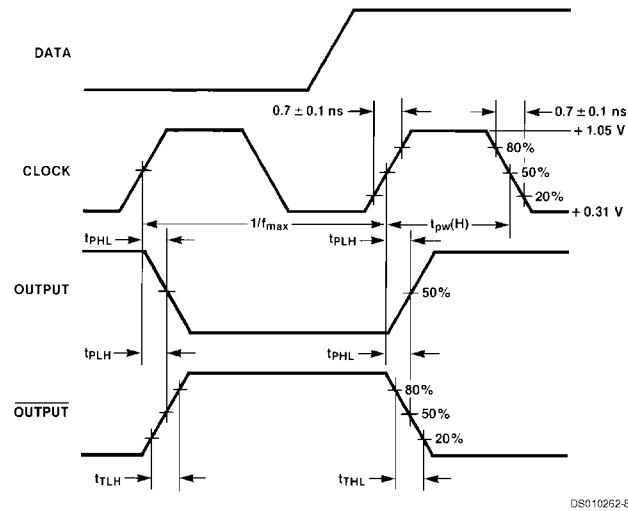


FIGURE 3. Propagation Delay (Clock) and Transition Times

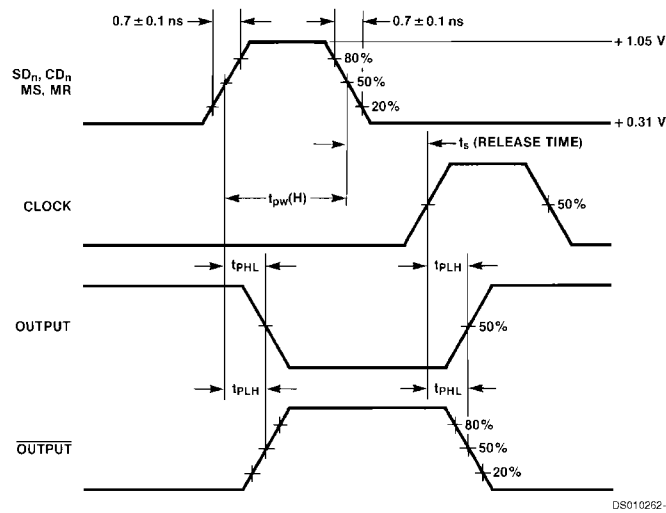


FIGURE 4. Propagation Delay (Resets)

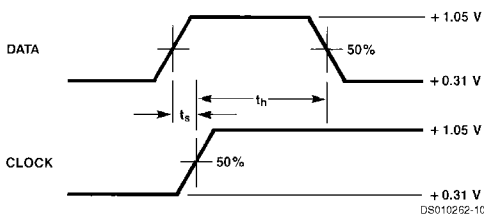


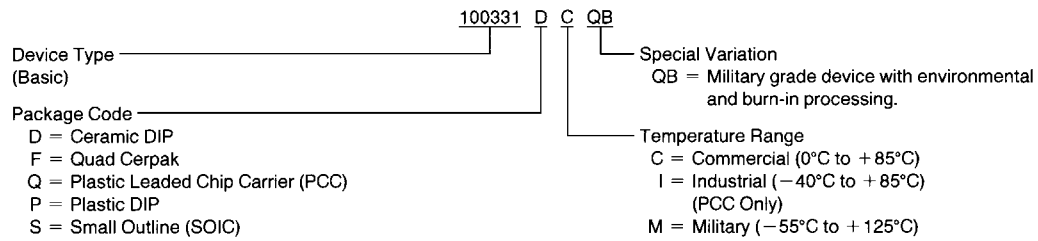
FIGURE 5. Data Setup and Hold Time

Note 14: t_s is the minimum time before the transition of the clock that information must be present at the data input.

Note 15: t_h is the minimum time after the transition of the clock that information must remain unchanged at the data input.

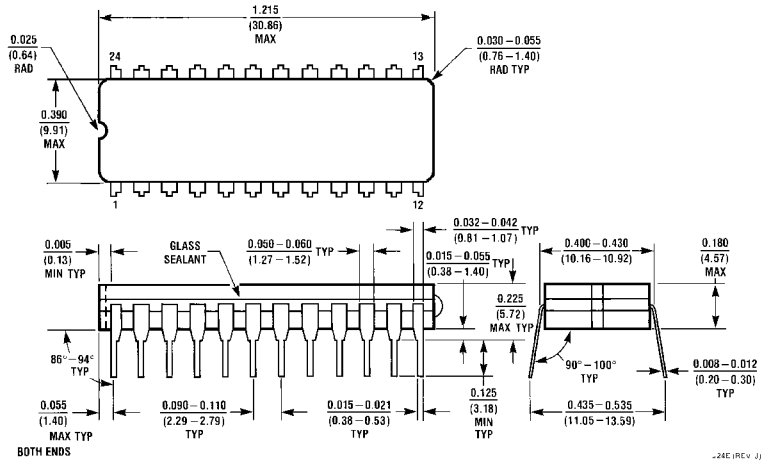
Ordering Information

The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:

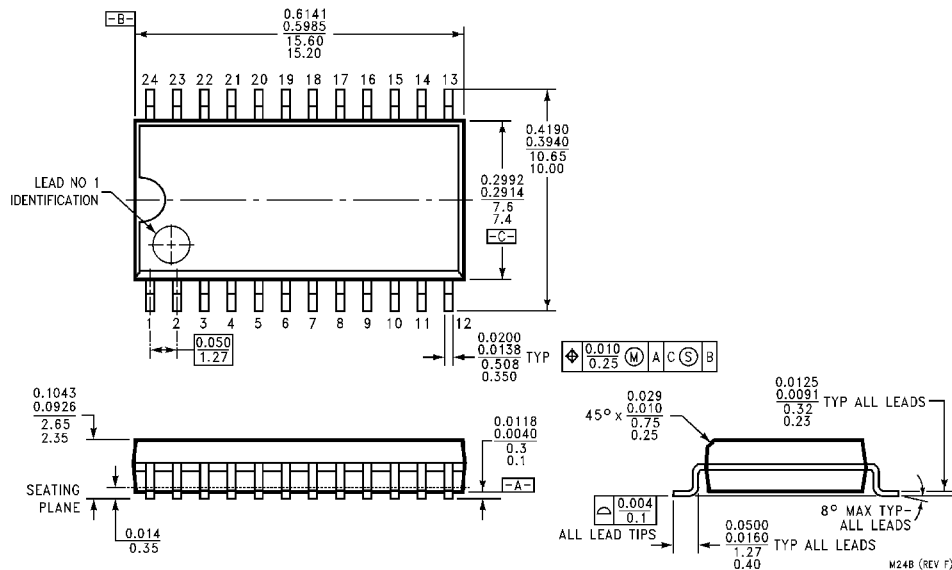


DS010262-11

Physical Dimensions inches (millimeters) unless otherwise noted

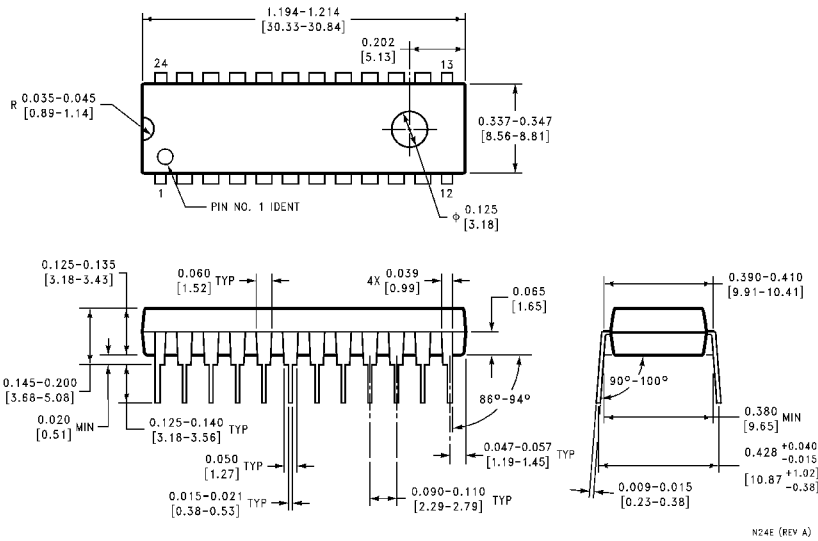


24-Lead Ceramic Dual-In-Line Package (0.400" Wide (D))
Package Number J24E

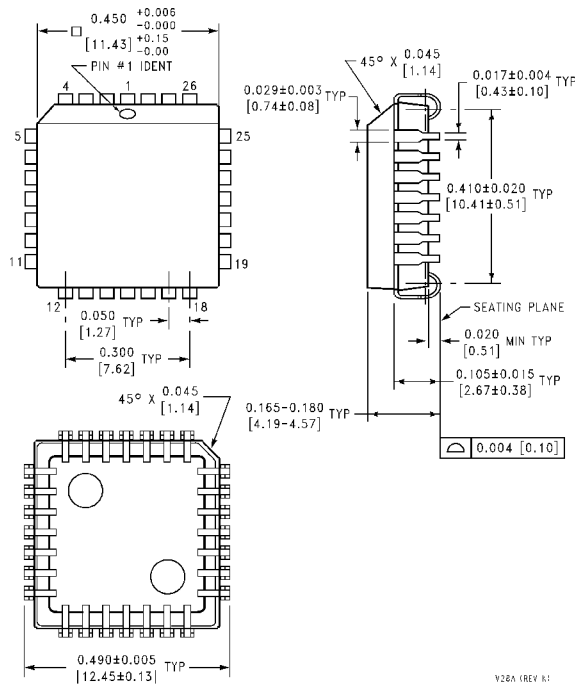


24-Lead Molded Package (0.300" Wide (S))
Package Number M24B

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

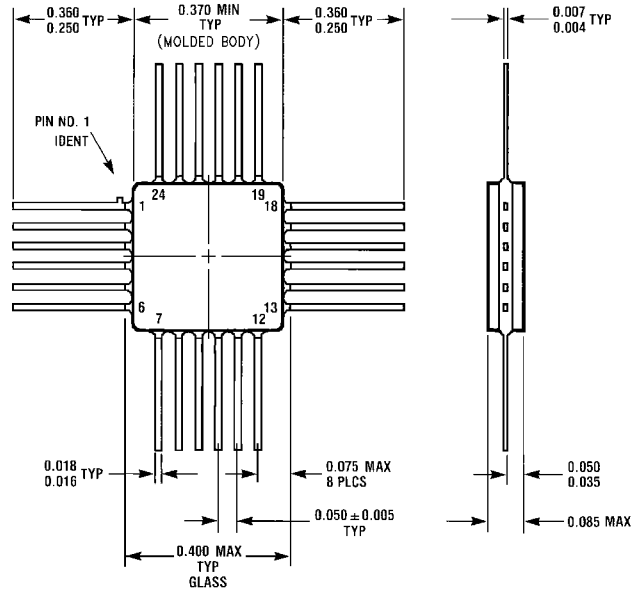


24-Lead Plastic Dual-In-Line Package (P)
Package Number N24E



28-Lead Plastic Chip Carrier (Q)
Package Number V28A

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



W24B (REV D)

**24-Lead Quad Cerpak (F)
Package Number W24B**

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